

### **IGBT3** Power Chip

#### Features:

- 1200V Trench + Field Stop technology
- low turn-off losses
- short tail current
- positive temperature coefficient
- easy paralleling

## This chip is used for:

• power module



### **Applications:**

drives

Chip Type	V <sub>CE</sub>	I <sub>Cn</sub>	Die Size	Package
SIGC12T120LE	1200V	8A	3.54 x 3.5 mm <sup>2</sup>	sawn on foil

### **MECHANICAL PARAMETER**

Raster size	3.54 x 3.5				
Emitter pad size (incl. gate pad)	2.028 x 2.028	mm <sup>2</sup>			
Gate pad size	1.107 x 0.702				
Area total / active	12.39 / 6.82				
Thickness	120	μm			
Wafer size	200	mm			
Max.possible chips per wafer	2243 pcs				
Passivation frontside	Photoimide				
Pad metal	3200 nm AlSiCu				
Backside metal	Ni Ag –system suitable for epoxy and soft solder die bonding				
Die bond	Electrically conductive glue or solder				
Wire bond	AI, <500μm				
Reject ink dot size	Ø 0.65mm ; max 1.2mm	1			
Recommended storage environment	Store in original container, in dry nitrogen, < 6 month at an ambient temperature of 23°C				



### **MAXIMUM RATINGS**

Parameter	Symbol	Value	Unit
Collector-Emitter voltage, T <sub>j</sub> =25 °C	V <sub>CE</sub>	1200	V
DC collector current, limited by T <sub>j max</sub>	I <sub>C</sub>	1)	А
Pulsed collector current, t <sub>p</sub> limited by T <sub>j max</sub>	I <sub>c,puls</sub>	24	А
Gate emitter voltage	V <sub>GE</sub>	±20	V
Maximum junction and storage temperature	$T_{\rm vj,max}$ , $T_{\rm stg}$	-55 <b>+</b> 150	°C
Short circuit data $^2$ V <sub>GE</sub> = 15V, V <sub>CC</sub> = 900V, $T_{vj}$ = 125°C	$t_{p,max}$	10	μs
Reverse bias safe operating area <sup>2)</sup> (RBSOA)	$I_{C,max} = 16A$	$V_{\text{CE,max}} = 1200\text{V}, T_{\text{vj,op}}$	≤ 125°C

<sup>1)</sup> depending on thermal properties of assembly

## **STATIC CHARACTERISTICS** (tested on wafer), $T_i$ =25 °C

Parameter	Symbol	Conditions	Value			Unit
Tarameter	Cymbol	Conditions	min.	typ.	max.	Omi
Collector-Emitter breakdown voltage	V <sub>(BR)CES</sub>	$V_{GE}$ =0V , $I_{C}$ = 0.5mA	1200			
Collector-Emitter saturation voltage	V <sub>CE(sat)</sub>	V <sub>GE</sub> =15V, I <sub>C</sub> =8A	1.4	1.7	2.1	V
Gate-Emitter threshold voltage	V <sub>GE(th)</sub>	$I_C$ =0.3mA , $V_{GE}$ = $V_{CE}$	5.0	5.8	6.5	
Zero gate voltage collector current	I <sub>CES</sub>	V <sub>CE</sub> =1200V , V <sub>GE</sub> =0V			1.23	μA
Gate-Emitter leakage current	$I_{GES}$	$V_{CE}$ =0V , $V_{GE}$ =20V			120	nA
Integrated gate resistor	R <sub>Gint</sub>			none		Ω

## **ELECTRICAL CHARACTERISTICS** (not subject to production test - verified by design / characterization)

Parameter	Symbol	Conditions		Value		Unit
raiailletei	Symbol	Conditions	min.	typ.	max.	Offic
Input capacitance	Ciss	V <sub>CE</sub> =25V,		600		
Output capacitance	Coss	$V_{GE}=0V$ ,		36		pF
Reverse transfer capacitance	Crss	f=1MHz		28		

<sup>&</sup>lt;sup>2)</sup> not subject to production test - verified by design/characterization



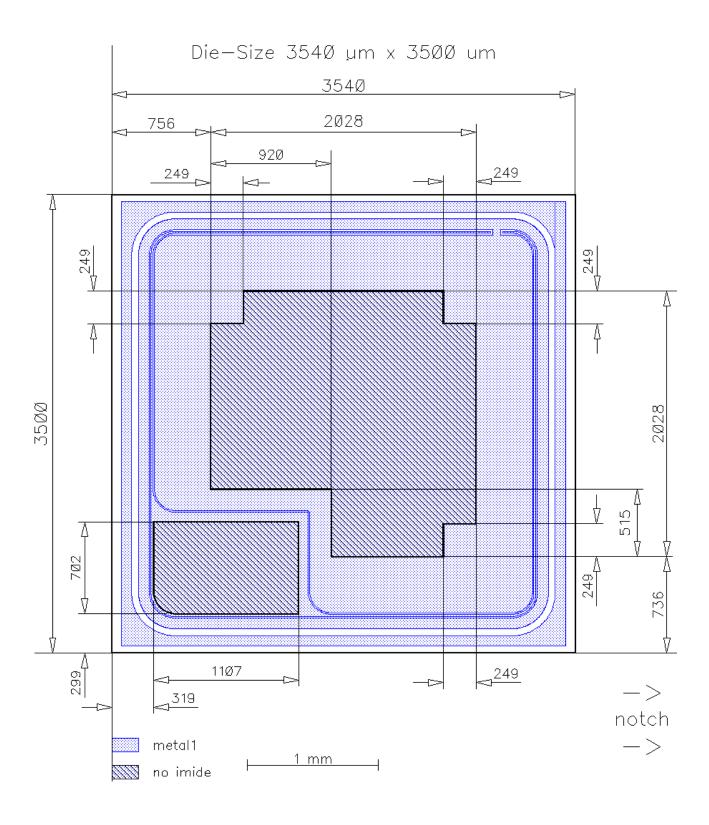
**SWITCHING CHARACTERISTICS** inductive load (not subject to production test - verified by design / characterization)

Parameter	Symbol	Conditions 1)		Value		Unit
raiailietei	Symbol	Conditions	min.	typ.	max.	Ullit
Turn-on delay time	$t_{d(on)}$	T <sub>j</sub> =125°C		40		
Rise time	t <sub>r</sub>	V <sub>CC</sub> =600V,		26		
Turn-off delay time	$t_{d(off)}$	I <sub>C</sub> =8A, V <sub>GE</sub> =0/15V,		570		μs
Fall time	t <sub>f</sub>	$R_G = 81\Omega$		140		

 $<sup>^{\</sup>rm 1)}$  values also influenced by parasitic L- and C- in measurement and package.



#### **CHIP DRAWING**





This chip data sheet refers to the device data sheet	IGW08T120	
DESCRIPTION		
AQL 0,65 for visual inspection according to failu	ire catalogue	
AQL 0,65 for visual inspection according to failute Electrostatic Discharge Sensitive Device accord		

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